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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, IR, POR, PWM, WDT
Number of I/O	40
Program Memory Size	4KB (4K x 8)
Program Memory Type	FLASH
EEPROM Size	256 x 8
RAM Size	1K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 28x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8l151c2t6

Contents

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3.6 Memories

The low-density STM8L151x2/3 devices have the following main features:

- Up to 1 Kbyte of RAM
- The non-volatile memory is divided into three arrays:
  - Up to 8 Kbyte of low-density embedded Flash program memory
  - 256 byte of data EEPROM
  - Option bytes.

The EEPROM embeds the error correction code (ECC) feature.

The option byte protects part of the Flash program memory from write and readout piracy.

3.7 DMA

A 4-channel direct memory access controller (DMA1) offers a memory-to-memory and peripherals-from/to-memory transfer capability. The 4 channels are shared between the following IPs with DMA capability: ADC1, I2C1, SPI1, USART1, the three Timers.

3.8 Analog-to-digital converter

- 12-bit analog-to-digital converter (ADC1) with 25 channels (including 1 fast channel), temperature sensor and internal reference voltage
- Conversion time down to 1 µs with f_{SYSCLK}= 16 MHz
- Programmable resolution
- Programmable sampling time
- Single and continuous mode of conversion
- Scan capability: automatic conversion performed on a selected group of analog inputs
- Analog watchdog
- Triggered by timer

Note: ADC1 can be served by DMA1.

3.9 Ultra-low-power comparators

The low-density STM8L151x2/3 embed two comparators (COMP1 and COMP2) sharing the same current bias and voltage reference. The voltage reference can be internal or external (coming from an I/O).

- One comparator with fixed threshold (COMP1).
- One comparator rail to rail with fast or slow mode (COMP2). The threshold can be one of the following:
  - External I/O
  - Internal reference voltage or internal reference voltage sub multiple (1/4, 1/2, 3/4)

The two comparators can be used together to offer a window function. They can wake up from Halt mode.

3.12.1 16-bit general purpose timers

- 16-bit autoreload (AR) up/down-counter
- 7-bit prescaler adjustable to fixed power of 2 ratios (1…128)
- 2 individually configurable capture/compare channels
- PWM mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)
- Synchronization with other timers or external signals (external clock, reset, trigger and enable)

3.12.2 8-bit basic timer

The 8-bit timer consists of an 8-bit up auto-reload counter driven by a programmable prescaler. It can be used for timebase generation with interrupt generation on timer overflow.

3.13 Watchdog timers

The watchdog system is based on two independent timers providing maximum security to the applications.

3.13.1 Window watchdog timer

The window watchdog (WWDG) is used to detect the occurrence of a software fault, usually generated by external interferences or by unexpected logical conditions, which cause the application program to abandon its normal sequence.

3.13.2 Independent watchdog timer

The independent watchdog peripheral (IWDG) can be used to resolve processor malfunctions due to hardware or software failures.

It is clocked by the internal LSI RC clock source, and thus stays active even in case of a CPU clock failure.

3.14 Beeper

The beeper function outputs a signal on the BEEP pin for sound generation. The signal is in the range of 1, 2 or 4 kHz.

Figure 5. STM8L151Gx UFQFPN28 package pinout

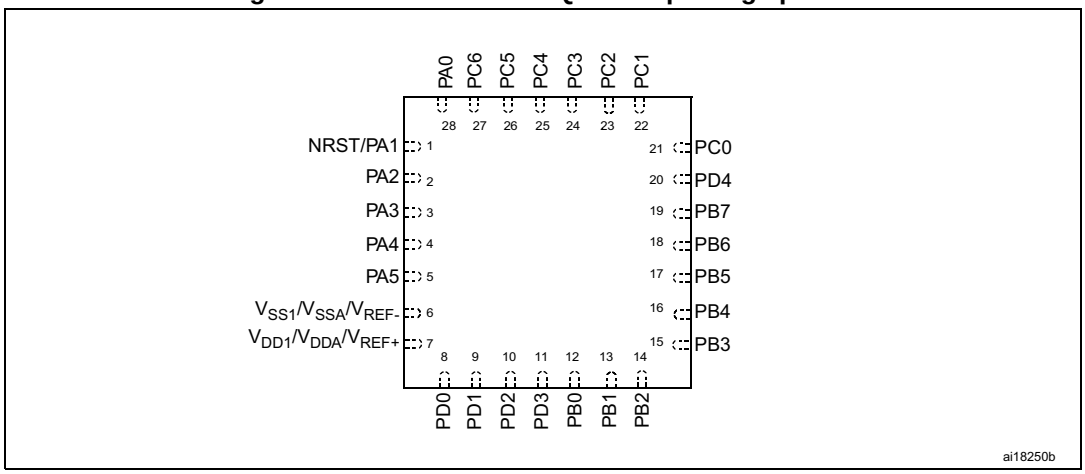


Figure 6. STM8L151Fx UFQFPN20 package pinout

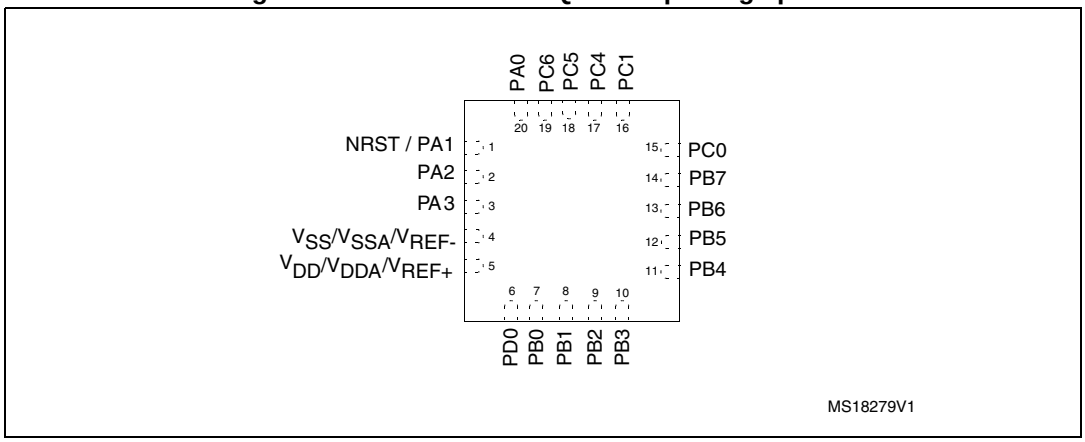


Figure 7. STM8L151Fx TSSOP20 package pinout

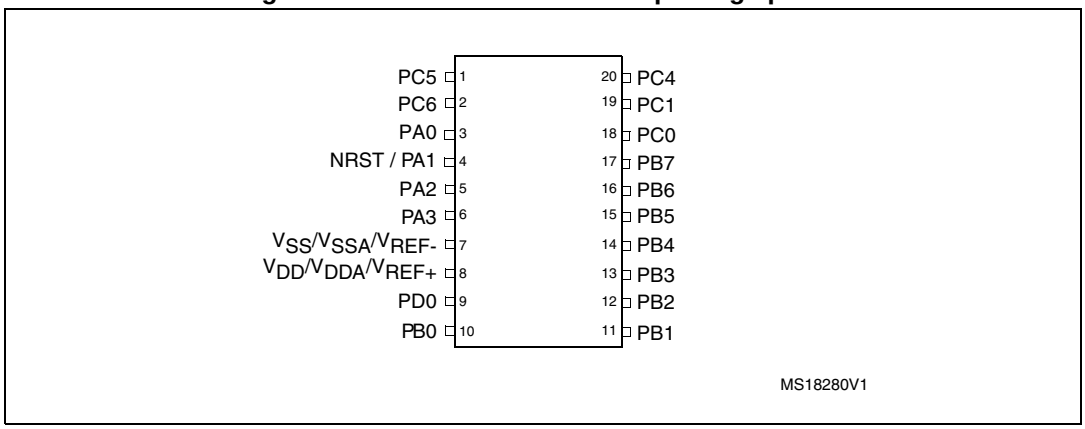


Table 8. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5055 to 0x00 506F	Reserved area (27 byte)			
0x00 5070	DMA1	DMA1_GCSR	DMA1 global configuration & status register	0xFC
0x00 5071		DMA1_GIR1	DMA1 global interrupt register 1	0x00
0x00 5072 to 0x00 5074		Reserved area (3 byte)		
0x00 5075		DMA1_C0CR	DMA1 channel 0 configuration register	0x00
0x00 5076		DMA1_C0SPR	DMA1 channel 0 status & priority register	0x00
0x00 5077		DMA1_C0NDTR	DMA1 number of data to transfer register (channel 0)	0x00
0x00 5078		DMA1_C0PARH	DMA1 peripheral address high register (channel 0)	0x52
0x00 5079		DMA1_C0PARL	DMA1 peripheral address low register (channel 0)	0x00
0x00 507A		Reserved area (1 byte)		
0x00 507B		DMA1_C0M0ARH	DMA1 memory 0 address high register (channel 0)	0x00
0x00 507C		DMA1_C0M0ARL	DMA1 memory 0 address low register (channel 0)	0x00
0x00 507D to 0x00 507E		Reserved area (2 byte)		
0x00 507F		DMA1_C1CR	DMA1 channel 1 configuration register	0x00
0x00 5080		DMA1_C1SPR	DMA1 channel 1 status & priority register	0x00
0x00 5081		DMA1_C1NDTR	DMA1 number of data to transfer register (channel 1)	0x00
0x00 5082		DMA1_C1PARH	DMA1 peripheral address high register (channel 1)	0x52
0x00 5083		DMA1_C1PARL	DMA1 peripheral address low register (channel 1)	0x00

Table 12. Option byte description

Option byte No.	Option description
OPT0	**ROP[7:0]** Memory readout protection (ROP) 0xAA: Disable readout protection (write access via SWIM protocol) Refer to Readout protection section in the STM8L15x and STM8L16x reference manual (RM0031).
OPT1	**UBC[7:0]** Size of the user boot code area 0x00: UBC is not protected. 0x01: Page 0 is write protected. 0x02: Page 0 and 1 reserved for the UBC and write protected. It covers only the interrupt vectors. 0x03: Page 0 to 2 reserved for UBC and write protected. 0x7F to 0xFF - All 128 pages reserved for UBC and write protected. The protection of the memory area not protected by the UBC is enabled through the MASS keys. Refer to User boot code section in the STM8L15x and STM8L16x reference manual (RM0031).
OPT2	Reserved
OPT3	**IWDG_HW:** Independent watchdog 0: Independent watchdog activated by software 1: Independent watchdog activated by hardware
	IWDG_HALT: Independent window watchdog off on Halt/Active-halt 0: Independent watchdog continues running in Halt/Active-halt mode 1: Independent watchdog stopped in Halt/Active-halt mode
	WWDG_HW: Window watchdog 0: Window watchdog activated by software 1: Window watchdog activated by hardware
	WWDG_HALT: Window window watchdog reset on Halt/Active-halt 0: Window watchdog stopped in Halt mode 1: Window watchdog generates a reset when MCU enters Halt mode
OPT4	**HSECNT**: Number of HSE oscillator stabilization clock cycles 0x00 - 1 clock cycle 0x01 - 16 clock cycles 0x10 - 512 clock cycles 0x11 - 4096 clock cycles
	LSECNT: Number of LSE oscillator stabilization clock cycles 0x00 - 1 clock cycle 0x01 - 16 clock cycles 0x10 - 512 clock cycles 0x11 - 4096 clock cycles Refer to *Table 31: LSE oscillator characteristics on page 74*.

9 Electrical parameters

9.1 Parameter conditions

Unless otherwise specified, all voltages are referred to V_{SS}.

9.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at T_A= 25 °C and T_A = T_A max (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics is indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean±3Σ).

9.1.2 Typical values

Unless otherwise specified, typical data is based on T_A = 25 °C, V_{DD} = 3 V. It is given only as design guidelines and is not tested.

Typical ADC1 accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean±2Σ).

9.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

9.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in *Figure 9*.

Figure 9. Pin loading conditions

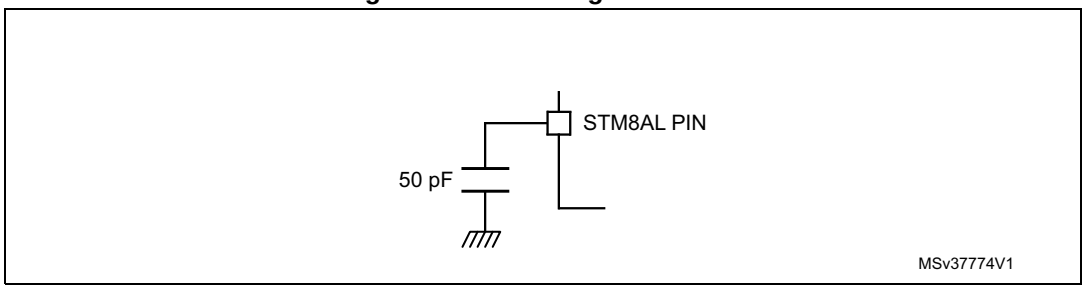


Table 19. Total current consumption in Run mode

Symbol	Parameter	Conditions[1]			Typ	Max				Unit
						55 °C	85 °C	105°C[2]	125 °C[2]	
$I_{DD(RUN)}$	Supply current in run mode[3]	All peripherals OFF, code executed from RAM, V_{DD} from 1.65 V to 3.6 V	HSI RC osc. (16 MHz)[4]	f_{CPU} = 125 kHz	0.39	0.47	0.49	0.52	0.55	mA
				f_{CPU} = 1 MHz	0.48	0.56	0.58	0.61	0.65	
				f_{CPU} = 4 MHz	0.75	0.84	0.86	0.91	0.99	
				f_{CPU} = 8 MHz	1.10	1.20	1.25	1.31	1.40	
				f_{CPU} = 16 MHz	1.85	1.93	2.12[6]	2.29[6]	2.36[6]	
			HSE external clock ($f_{CPU}=f_{HSE}$)[5]	f_{CPU} = 125 kHz	0.05	0.06	0.09	0.11	0.12	
				f_{CPU} = 1 MHz	0.18	0.19	0.20	0.22	0.23	
				f_{CPU} = 4 MHz	0.55	0.62	0.64	0.71	0.77	
				f_{CPU} = 8 MHz	0.99	1.20	1.21	1.22	1.24	
				f_{CPU} = 16 MHz	1.90	2.22	2.23[6]	2.24[6]	2.28[6]	
			LSI RC osc. (typ. 38 kHz)	$f_{CPU} = f_{LSI}$	0.040	0.045	0.046	0.048	0.050	
			LSE external clock (32.768 kHz)	$f_{CPU} = f_{LSE}$	0.035	0.040	0.048[6]	0.050	0.062	
$I_{DD(RUN)}$	Supply current in Run mode	All peripherals OFF, code executed from Flash, V_{DD} from 1.65 V to 3.6 V	HSI RC osc.[7]	f_{CPU} = 125 kHz	0.43	0.55	0.56	0.58	0.62	mA
				f_{CPU} = 1 MHz	0.60	0.77	0.80	0.82	0.87	
				f_{CPU} = 4 MHz	1.11	1.34	1.37	1.39	1.43	
				f_{CPU} = 8 MHz	1.90	2.20	2.23	2.31	2.40	
				f_{CPU} = 16 MHz	3.8	4.60	4.75	4.87	4.88	
			HSE external clock ($f_{CPU}=f_{HSE}$) [5]	f_{CPU} = 125 kHz	0.30	0.36	0.39	0.44	0.47	
				f_{CPU} = 1 MHz	0.40	0.50	0.52	0.55	0.56	
				f_{CPU} = 4 MHz	1.15	1.31	1.40	1.45	1.48	
				f_{CPU} = 8 MHz	2.17	2.33	2.44	2.56	2.77	
				f_{CPU} = 16 MHz	4.0	4.46	4.52	4.59	4.77	
			LSI RC osc.	$f_{CPU} = f_{LSI}$	0.110	0.123	0.130	0.140	0.150	
			LSE ext. clock (32.768 kHz)[8]	$f_{CPU} = f_{LSE}$	0.100	0.101	0.104	0.119	0.122	

1. All peripherals OFF, V_{DD} from 1.65 V to 3.6 V, HSI internal RC osc., $f_{CPU}=f_{SYSCLK}$
2. For devices with suffix 3
3. CPU executing typical data processing

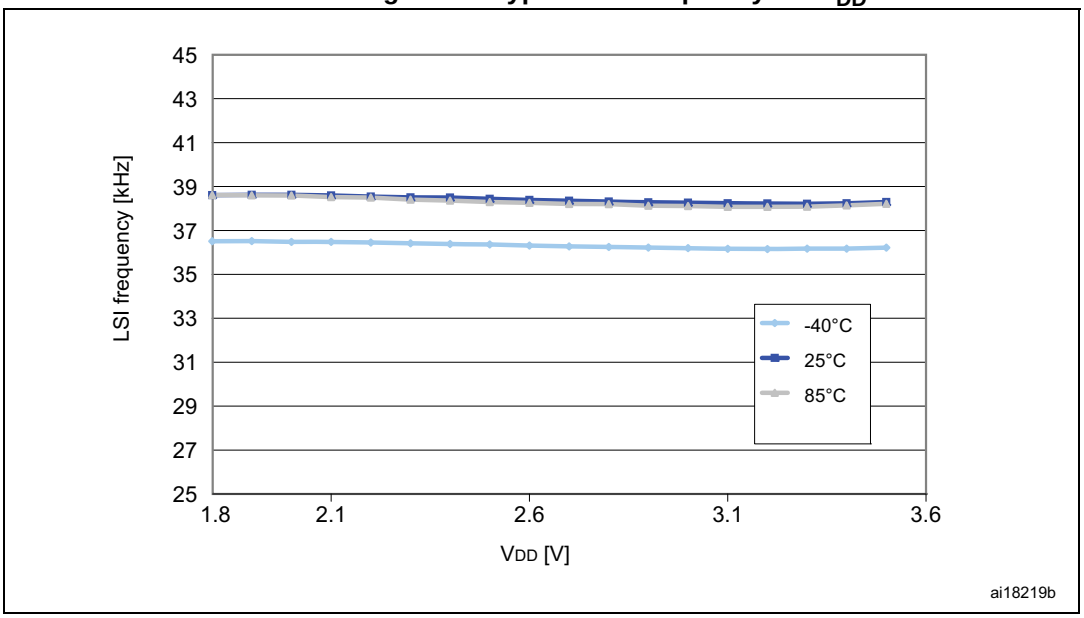
In the following table, data is based on characterization results, unless otherwise specified.

Table 25. Total current consumption and timing in Halt mode at V_{DD} = 1.65 to 3.6 V

Symbol	Parameter	Condition(1)(2)	Typ	Max	Unit
$I_{DD(Halt)}$	Supply current in Halt mode (Ultra-low-power ULP bit =1 in the PWR_CSR2 register)	T_A = -40 °C to 25 °C	350	1400(3)	nA
		T_A = 55 °C	580	2000	
		T_A = 85 °C	1160	2800(3)	
		T_A = 105 °C	2560	6700(3)	
		T_A = 125 °C	4.4	13(3)	µA
$I_{DD(WUHalt)}$	Supply current during wakeup time from Halt mode (using HSI)	-	2.4	-	mA
$t_{WU\_HSI(Halt)}$(4)(5)	Wakeup time from Halt to Run mode (using HSI)	-	4.7	7	µs
$t_{WU\_LSI(Halt)}$ (4)(5)	Wakeup time from Halt mode to Run mode (using LSI)	-	150	-	µs

1. T_A = -40 to 125 °C, no floating I/O, unless otherwise specified.
2. T_A > 85 °C is valid only for devices with suffix 3 temperature range.
3. Tested in production.
4. ULP=0 or ULP=1 and FWU=1 in the PWR_CSR2 register.
5. Wakeup time until start of interrupt vector fetch.
The first word of interrupt routine is fetched 4 CPU cycles after t_{WU}.

Figure 19. Typical LSI frequency vs. V_{DD}



9.3.5 Memory characteristics

T_A = -40 to 125 °C unless otherwise specified.

Table 34. RAM and hardware registers

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{RM}	Data retention mode (1)	Halt mode (or Reset)	1.65	-	-	V

1. Minimum supply voltage without losing data stored in RAM (in Halt mode or under Reset) or in hardware registers (only in Halt mode). Guaranteed by characterization, not tested in production.

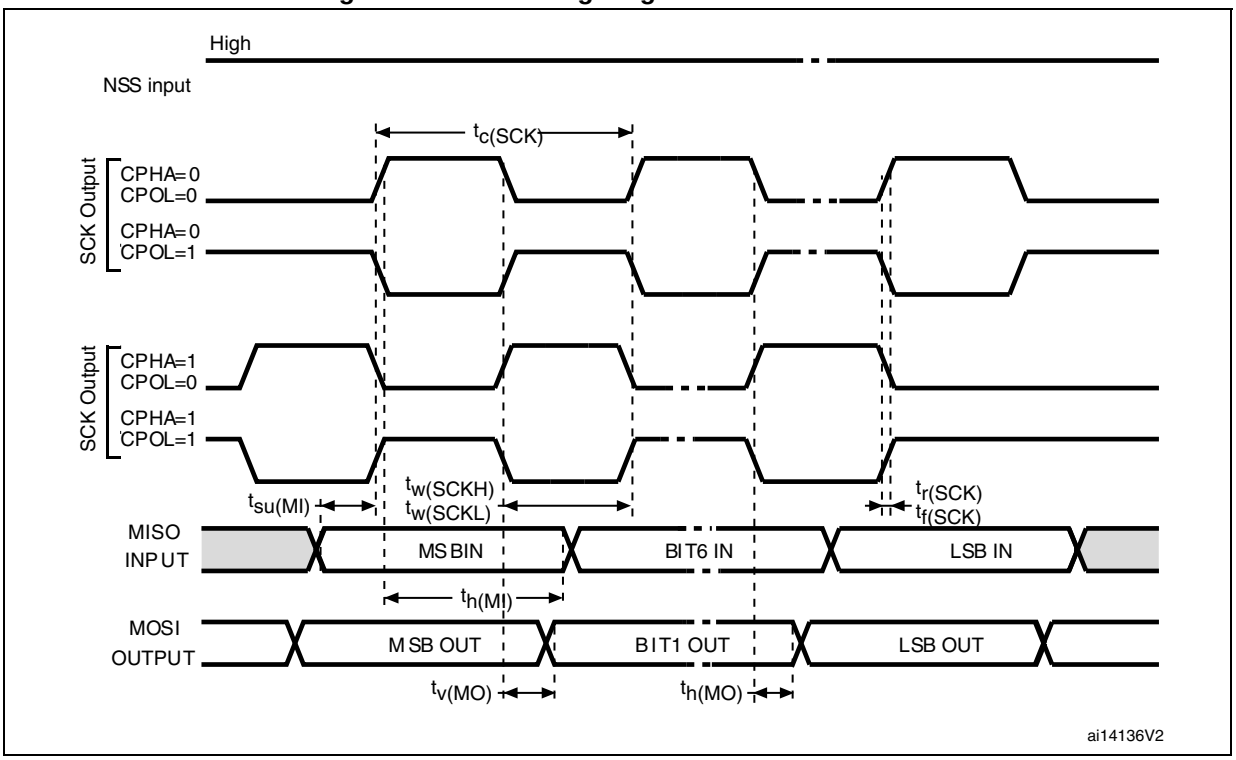
Flash memory

Table 35. Flash program and data EEPROM memory

Symbol	Parameter	Conditions	Min	Typ	Max (1)	Unit
V_{DD}	Operating voltage (all modes, read/write/erase)	f_{SYSCLK} = 16 MHz	1.65	-	3.6	V
t_{prog}	Programming time for 1 or 64 bytes (block) erase/write cycles (on programmed byte)	-	-	6	-	ms
	Programming time for 1 to 64 bytes (block) write cycles (on erased byte)	-	-	3	-	ms
I_{prog}	Programming/ erasing consumption	T_A=+25 °C, V_{DD} = 3.0 V	-	0.7	-	mA
		T_A=+25 °C, V_{DD} = 1.8 V	-	0.7	-	
t_{RET} (2)	Data retention (program memory) after 10000 erase/write cycles at T_A= –40 to +85 °C (3 and 6 suffix)	T_{RET} = +85 °C	30(1)	-	-	years
	Data retention (program memory) after 10000 erase/write cycles at T_A= –40 to +125 °C (3 suffix)	T_{RET} = +125 °C	5(1)	-	-	
	Data retention (data memory) after 300000 erase/write cycles at T_A= –40 to +85 °C (3 and 6 suffix)	T_{RET} = +85 °C	30(1)	-	-	
	Data retention (data memory) after 300000 erase/write cycles at T_A= –40 to +125 °C (3 suffix)	T_{RET} = +125 °C	5(1)	-	-	
N_{RW} (3)	Erase/write cycles (program memory)	T_A = –40 to +85 °C (3 and 6 suffix), T_A = –40 to +105 °C (3 suffix) or T_A = –40 to +125 °C (3 suffix)	10(1)	-	-	kcycles
	Erase/write cycles (data memory)		300(1) (4)	-	-	

1. Data based on characterization results, not tested in production.
2. Conforming to JEDEC JESD22a117
3. The physical granularity of the memory is 4 bytes, so cycling is performed on 4 bytes even when a write/erase operation addresses a single byte.
4. Data based on characterization performed on the whole data memory.

Figure 35. SPI1 timing diagram - master mode(1)



1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

In the following table, data is guaranteed by design, not tested in production.

Table 47. Comparator 2 characteristics

Symbol	Parameter	Conditions	Min	Typ	Max(1)	Unit
V_{DDA}	Analog supply voltage	-	1.65	-	3.6	V
T_A	Temperature range	-	-40	-	125	°C
V_{IN}	Comparator 2 input voltage range	-	0	-	V_{DDA}	V
t_{START}	Comparator startup time	Fast mode	-	15	20	µs
		Slow mode	-	20	25	
$t_{d\ slow}$	Propagation delay in slow mode(2)	1.65 V ≤ V_{DDA} ≤ 2.7 V	-	1.8	3.5	
		2.7 V ≤ V_{DDA} ≤ 3.6 V	-	2.5	6	
$t_{d\ fast}$	Propagation delay in fast mode(2)	1.65 V ≤ V_{DDA} ≤ 2.7 V	-	0.8	2	
		2.7 V ≤ V_{DDA} ≤ 3.6 V	-	1.2	4	
V_{offset}	Comparator offset error	-	-	±4	±20	mV
I_{COMP2}	Current consumption(3)	Fast mode	-	3.5	5	µA
		Slow mode	-	0.5	2	

1. Based on characterization, not tested in production.
2. The delay is characterized for 100 mV input step with 10 mV overdrive on the inverting input, the non-inverting input set to the reference.
3. Comparator consumption only. Internal reference voltage not included.

Figure 39. Power supply and reference decoupling (V_{REF+} not connected to V_{DDA})

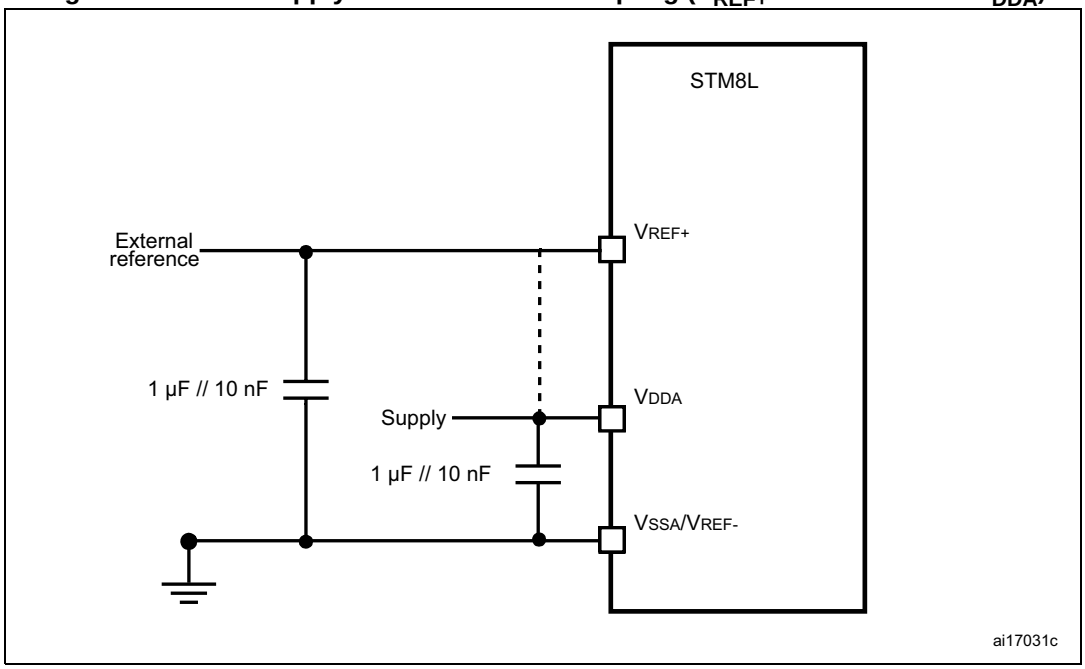
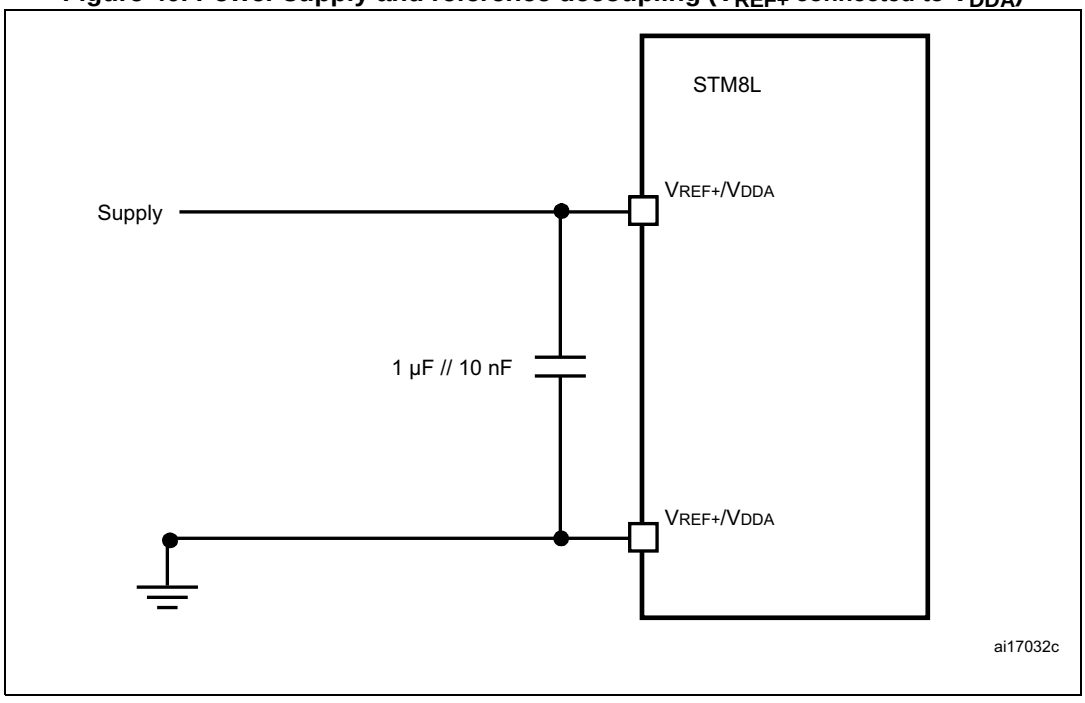


Figure 40. Power supply and reference decoupling (V_{REF+} connected to V_{DDA})



A device reset allows normal operations to be resumed. The test results are given in the table below based on the EMS levels and classes defined in application note AN1709.

Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

Table 53. EMS data

Symbol	Parameter	Conditions		Level/ Class
V_{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V_{DD} = 3.3 V, T_A = +25 °C, f_{CPU}= 16 MHz, conforms to IEC 61000		2B
V_{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V_{DD} and V_{SS} pins to induce a functional disturbance	V_{DD} = 3.3 V, T_A = +25 °C, f_{CPU} = 16 MHz, conforms to IEC 61000	Using HSI	4A
			Using HSE	2B

Electromagnetic interference (EMI)

Based on a simple application running on the product (toggling 2 LEDs through the I/O ports), the product is monitored in terms of emission. This emission test is in line with the norm IEC61967-2 which specifies the board and the loading of each pin.

Table 54. EMI data (1)

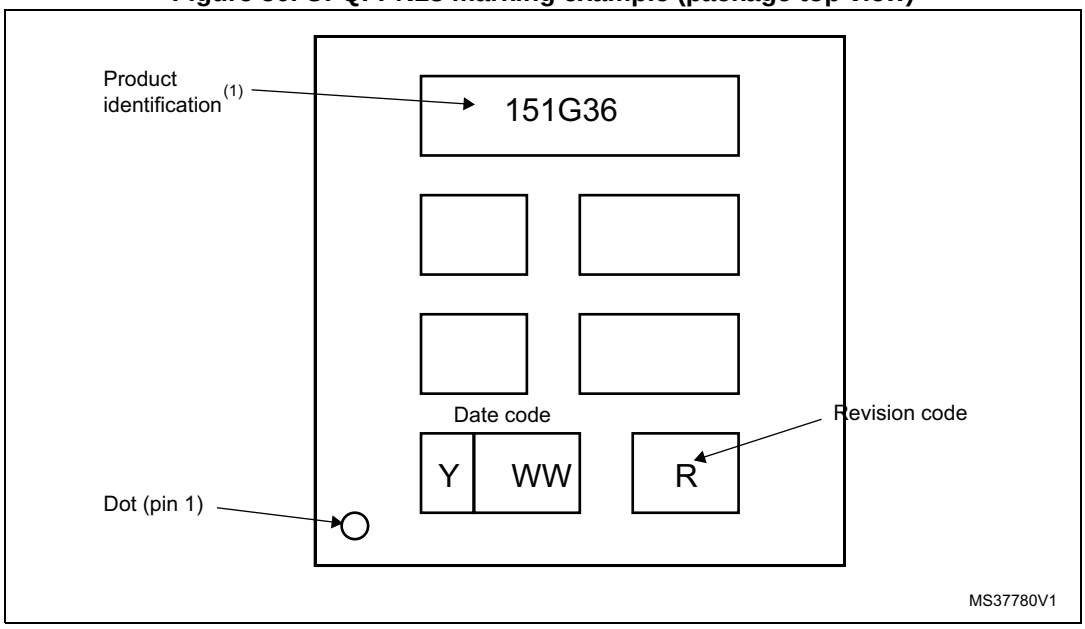
Symbol	Parameter	Conditions	Monitored frequency band	Max vs. 16 MHz	Unit
S_{EMI}	Peak level	V_{DD} = 3.6 V, T_A = +25 °C, LQFP48 conforming to IEC61967-2	0.1 MHz to 30 MHz	-3	dBµV
			30 MHz to 130 MHz	9	
			130 MHz to 1 GHz	4	
			SAE EMI Level	2	-

1. Not tested in production.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 50. UFQFPN28 marking example (package top view)



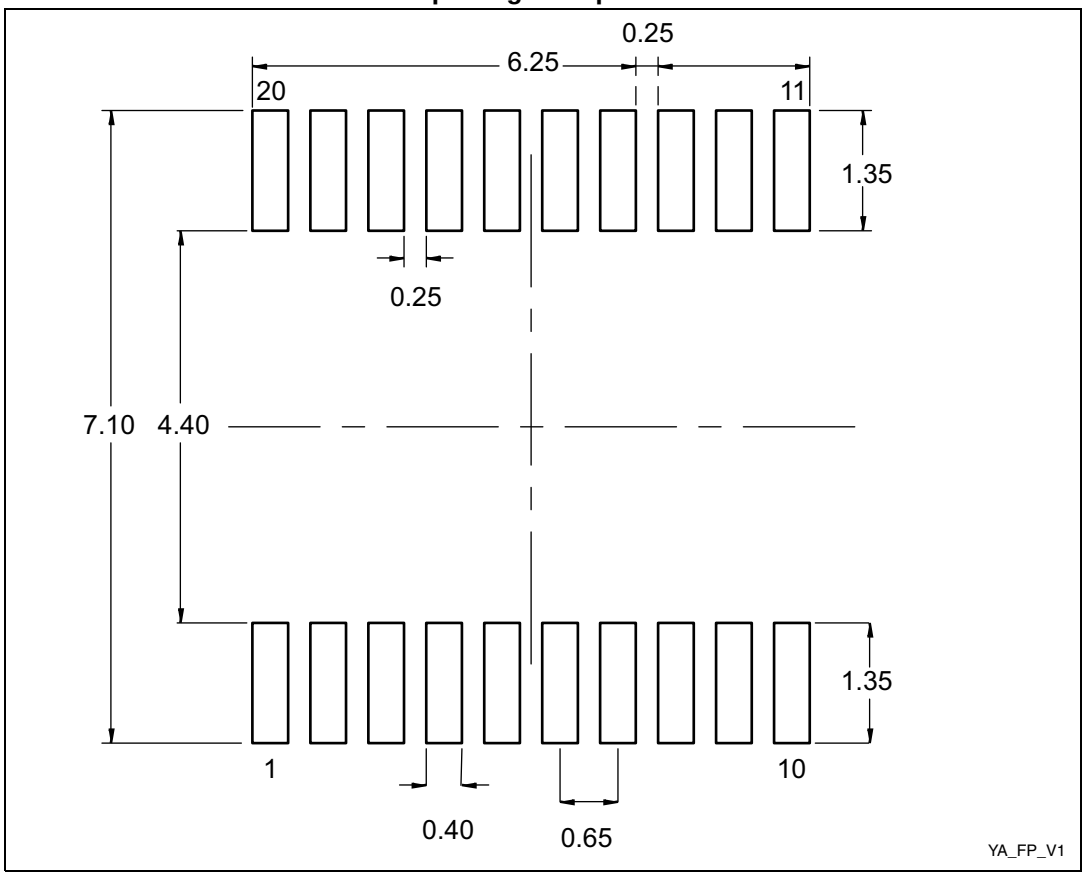
1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Table 61. TSSOP20 – 20-lead thin shrink small outline, 6.5 x 4.4 mm, 0.65 mm pitch, package mechanical data (continued)

Symbol	millimeters			inches[1]		
	Min.	Typ.	Max.	Min.	Typ.	Max.
k	0°	-	8°	0°	-	8°
aaa	-	-	0.100	-	-	0.0039

1. Values in inches are converted from mm and rounded to four decimal digits.

Figure 55. TSSOP20 – 20-lead thin shrink small outline, 6.5 x 4.4 mm, 0.65 mm pitch, package footprint

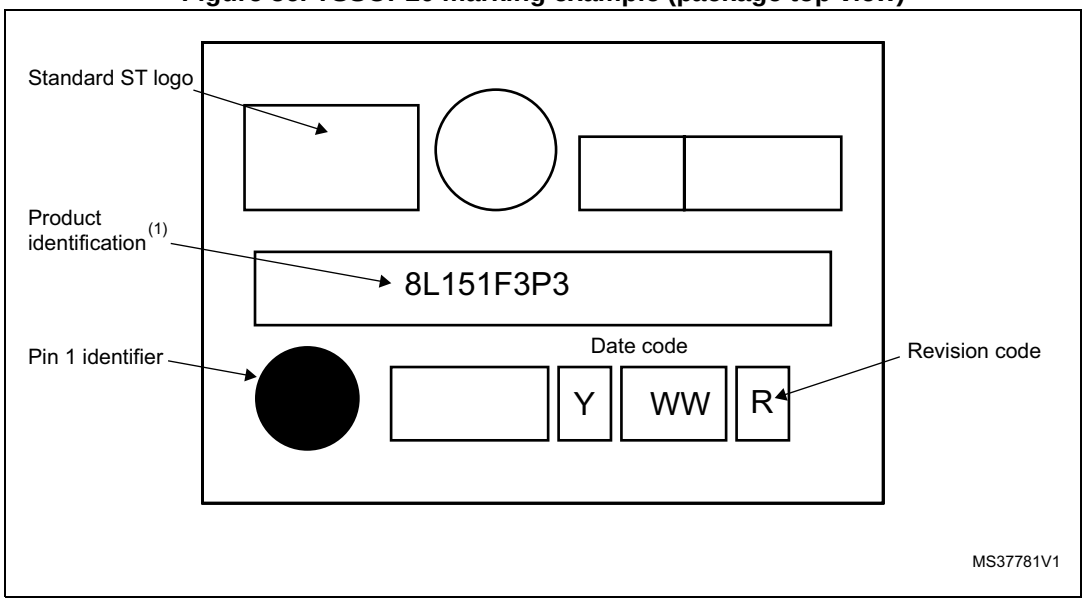


1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 56. TSSOP20 marking example (package top view)



1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.